


<b>Search Notes</b>  	<b>Application/Control No.</b>  10814723	<b>Applicant(s)/Patent Under Reexamination</b>  OFEK ET AL.
	<b>Examiner</b>  TAN TRINH	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	25, 63.4, 422, 101, 132, 524, 560, 562, 273, 276.233.1, 562.1,	11-01-08	TT
370	352, 353, 334, 278	11-01-08	TT
343	757, 702, 700, 754, 766, 359, 74, 766758, 879	11-01-08	TT

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	11-01-08	TT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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